

Maximum Ratings ($@T_A = +25^{\circ}C$, unless otherwise specified.)

Characteristic			Symbol	Value	Units
Drain-Source Voltage			V_{DSS}	30	V
Gate-Source Voltage			V_{GSS}	±25	V
Continuous Drain Current (Note 7) V _{GS} = 10V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	7.5 6.0	Α
	t<10s	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	9.8 7.7	Α
Continuous Drain Current (Note 7) V _{GS} = 4.5V	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	6.4 5.0	Α
	t<10s	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	8.4 6.6	А
Maximum Continuous Body Diode Forward Current (Note 7)			Is	2	Α
Pulsed Drain Current (10µs pulse, duty cycle = 1%)			I _{DM}	42	Α
Avalanche Current (Notes 8 & 9) L = 0.1mH			I _{AR}	17	Α
Repetitive Avalanche Energy (Notes 8 & 9) L = 0.1mH			E _{AR}	14	mJ

Thermal Characteristics

Characteristic		Symbol	Value	Units	
Total Power Dissipation (Note 6)		P_{D}	1.17	W	
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	П	107	°C/W	
Thermal Resistance, Juniction to Ambient (Note 6)	t<10s	$R_{\theta JA}$	61		
Total Power Dissipation (Note 7)		P_{D}	1.5	W	
Thermal Resistance, Junction to Ambient (Note 7)	Steady State	D	83	°C/W	
Thermal Resistance, Junction to Ambient (Note 7)	t<10s	$R_{\theta JA}$	49		
Thermal Resistance, Junction to Case		$R_{ heta JC}$	14.5		
Operating and Storage Temperature Range		$T_{J_1}T_{STG}$	-55 to 150	°C	

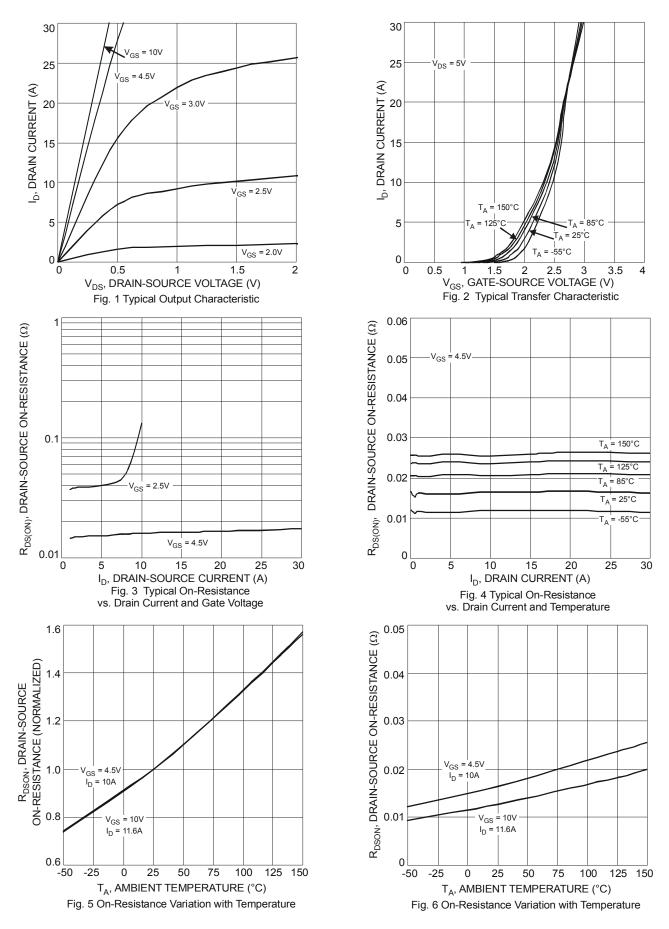
Electrical Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 10)							
Drain-Source Breakdown Voltage	BV _{DSS}	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current T _J = +25°C	I _{DSS}	-	_	1.0	μΑ	$V_{DS} = 30V, V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	1	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 10)	ON CHARACTERISTICS (Note 10)						
Gate Threshold Voltage	V _{GS(th)}	8.0		1.6	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance	D		12 16	16 22	mΩ	$V_{GS} = 10V, I_D = 9A$	
Static Drain-Source On-Resistance	R _{DS(on)}	_				$V_{GS} = 4.5V, I_D = 7A$	
Forward Transfer Admittance	Y _{fs}	_	8	_	S	V _{DS} = 10V, I _D = 9A	
Diode Forward Voltage	V_{SD}	_	0.72	0.94	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS (Note 11)							
Input Capacitance	C _{iss}	_	798	_	pF		
Output Capacitance	Coss	1	128		рF	V _{DS} = 10V, V _{GS} = 0V, f = 1.0MHz	
Reverse Transfer Capacitance	C _{rss}	_	122		pF		
Gate Resistance	R_{g}	_	1.37	_	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge	Qg	_	8.56	_	nC	V _{GS} = 5V, V _{DS} = 15V, I _D = 9A	
Gate-Source Charge	Q _{gs}	_	1.8	_	nC		
Gate-Drain Charge	Q _{gd}	_	2.5	_	nC		
Turn-On Delay Time	t _{D(on)}	_	5.03	_	ns	V_{DD} = 15V, V_{GEN} = 10V, R_{L} = 15 Ω , R_{G} = 6 Ω , I_{D} = 1A	
Turn-On Rise Time	t _r	_	4.50	_	ns		
Turn-Off Delay Time	t _{D(off)}	_	26.33	_	ns		
Turn-Off Fall Time	t _f	_	8.55	_	ns		

Notes:

- 6. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
 7. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
 8. I_{AR} and E_{AR} rating are based on low frequency and duty cycles to keep T_J = +25°C.
 9. Applicable to products manufactured with Data Code "1146" (Nov, 2011) and newer.
 10. Short duration pulse test used to minimize self-heating effect.
 11. Guaranteed by design. Not subject to product testing.







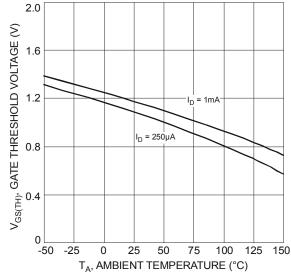
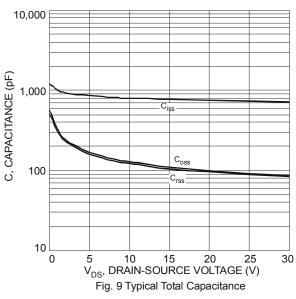


Fig. 7 Gate Threshold Variation vs. Ambient Temperature



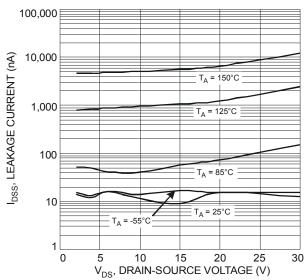
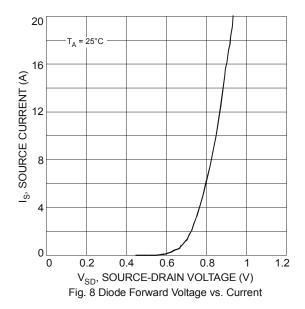
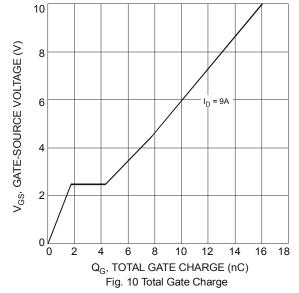
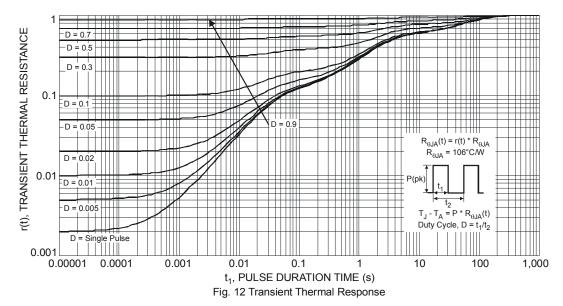


Fig. 11 Typical Leakage Current vs. Drain-Source Voltage



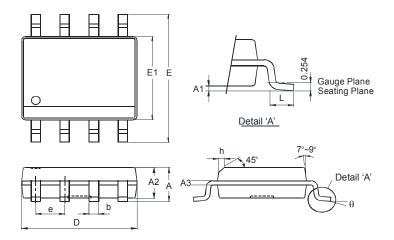






Package Outline Dimensions

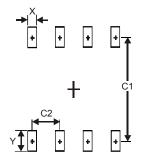
Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



SO-8					
Dim	Min	Max			
Α	-	1.75			
A1	0.10	0.20			
A2	1.30	1.50			
A3	0.15	0.25			
b	0.3	0.5			
D	4.85	4.95			
Е	5.90	6.10			
E1	3.85	3.95			
е	e 1.27 Typ				
h	-	0.35			
L	0.62	0.82			
θ	0°	8°			
All Dimensions in mm					

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
X	0.60
Υ	1.55
C1	5.4
C2	1.27



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